

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/004,023 HU ET AL.	
		Examiner	Art Unit Feben M Haile	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,684,354 B2	01-2004	Fukushima et al.	714/718
	B	US-6,445,706 B1	09-2002	Fransson et al.	370/412
	C	US-2004/0008714 A1	01-2004	Jones, David E.	370/428
	D	US-2004/0141510	07-2004	Blanc et al.	370/401
	E	US-2002/0057706	05-2002	MICHAEL, HERMAN	370/412
	F	US-2002/0044556	04-2002	Ando et al.	370/395.42
	G	US-2002/0021700	02-2002	Hata et al.	370/395.42
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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